V14a



On Membrane Attenuators for 60 GHz Loopback



DRMFACTOR[™]

Transceiver Testing

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- Background
- Problem Discussion
- Analysis
- Solution
- Design
- Validation
- Conclusions

Problem Statement

STMicroelectronics has observed variable attenuation across sites in their Receiver Signal Strength Indicator (RSSI) signal causing test failures and delays in their production test.

Technology Background SFORMFACTOR

STMicroelectronics ST60A3

60 GHz V-Band transceiver for contactless connectivity up to 480 Mbps



FormFactor Pyramid Probe P800s

Most widely qualified wafer test solution for production test





- Frequency range to 67 GHz with better than -10 dB Return Loss (RL) to maximize test accuracy out to specified frequency
- Multi-site 5G antenna and RFFE die testing
- Probe geometries engineered for low contact resistance on pads and solder

Test Strategy

Measurement Challenge: To test the ST60A3 requires expensive equipment. This results in high cost of test. To reduce cost, a test technique called loopback testing was employed.

Implantation Requirements:

- Loopback path needs a high level of attenuation to ensure the transmitter (Tx) doesn't saturate the receiver (Rx).
- Wafer on bump testing
- Use x8 parallelism



Tx and Rx blocks are tested by looping one to the other:

Loopback Testing

• Output power at TX

- P_{OUT} calibrated at fixed level and verified through TSSI (Transmitter signal strength indicator)
- Input power at RX
 - P_{IN} at RX is evaluated from RSSI (Receiver signal strength indicator) measurement on ATE (in mV)

This presentation focuses on RSSI data collection



Problem Discussion

Observed:

There is more than 3 dB (110 mV) difference between site 1 and site 8.

Maximum acceptable site to site delta = 50 mV 300 (6 x per site standard deviation) 240 mV з 250 5 RSSI 200 110 mV 8 150 130 mV Referen points: 100 1 2 З 4 5 6 7 8 The problem is due to more than 3 dB of variation Next let's look at what we did to solve it. SWTest | June 5 - 7, 2023

RSSI (P_{IN}) Measured for Complete Wafer Using x8 P800s

Problem Discussion

Observed variability in measurement data for site to site (8 sites), wafer to wafer, probe card to probe card and tester to tester. RSSI (PIN) Measured for Multiple Wafer Using x8 P800s Line by: (None) 280 Color by 260 Site 240 1 2 220 RSSI 200 4 5 180 6 160 8 140 120 100 80 Wafer 3 Wafer 5 Wafer 1 Wafer 2 Wafer 4 Wafer 6 Note: Each plot is 1 tested die on a wafer Data comes from different test setup conditions (different testers, different probe cards & cores) Data below red line resulted in a test failure. **!! Yield loss impact !! And CpK below 1** SWTest | June 5 - 7, 2023

Model and Hypothesis

- Model 1: Core + PCB X
- Model 2: Core to Board Interface (CBI) Simulation ¥
- Model 3: Semi Rigid Cable <u>×</u>
- Model 4: Bridge Beam + Shim + PC interaction

Core + PCB Testing

Observation: Not all bumps at the CBI make contact with the PCB pad.

Hypothesis: Interference between membrane & coax makes only 1 contact/imprint at CBI.

- Built a model to study bump & pad.
- Model shows no significant difference with 1 or both bumps touching down on PCB
- Kapton tape is 30 um thick and produced a 3 dB effect. (similar difference in RSSI)



Not the

Problem

-50.00

Semi Rigid Cable

Observation: Semi rigid cable was length matched (600 ps +/- 2.5 ps) but some had more bends than others.

Not the

Problem

Hypothesis: Bends in cable causing discontinuities that are leading to attenuation issues.

- Minimum on sites 4 & 5 and most on 1 & 8. (also max number of cable bends)
- It's known that there is about 3 dB difference between site 1 and site 4.
- IL measurements of site 1 & 4 show < 0.2 dB difference.



Bridge Beam vs Core Interference

Observation: Different test cells were producing different results for the same Probe Card (PC)

Hypothesis: Lack of planarity and uniform pressure of the bridge beam and core was causing attenuation issues.

- Special fixture was designed and manufactured to measure the interference
- It was found that the planarity and interference was within spec for the test setup

Not the Problem

Bridge

beam



Bridge Beam Interaction

Observation: Numerous configurations have shown that mechanical forces negatively impact the RSSI.

Hypothesis: There is a PCB + Core interaction that affects the RSSI measurements

- Using combinations of shims, docking and undocking, tape and Over Drive (OD) it was possible to affect the RSSI level measured.
- This effect was not seen on any other application. Was unique to this design.
- Bridge beam interaction effects were eliminated by moving all attenuators from the PCB to the membrane.





RSSI Manipulation



- Attenuator Trade Off Analysis
- Coupler Theory
- Design Considerations
- 50 Ω Trick
- Simulation
- Measurements (Validation)
- Results (Summary)

Using "on membrane attenuators" solves our problem. Let's look at how this is implemented...

Attenuator Trade Off Analysis

Design Consideration	Resistive	Coupler	TX Line
60 GHz Operation			
RL Performance			
Crosstalk/Coupling	N/A	N/A	
Area (minimum)			
Design Complexity			
Routing Considerations			
Assembly Error			
SMT Quantity			
= bad = neutral = good Next let's look at what a coupler attenuator is!			
Note:			
Resistive and TX line attenuator is least suitable. It will not be considered any further in this presentation			
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Coupler Theory

Solution

Coupler Definition (Ideal): Directional device where power suppled to port 1 (input) is coupled to port 3 (coupled port) while the remaining power is delivered to port 2 (transmitted port). <u>There is no power at port 4 (isolated port)</u>.



Design Considerations

Design Requirements for Attenuator

- Center Frequency (fc) = 60.5 GHz
- PTX MAX = 6 dBm ~ 4 mW -> 01005 resistors
- Attenuation = 26 dB

Solution

• Bandwidth (BW) = 500 MHz



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Attenuation (S21) vs. Gap Size @ 60 GHz R1005





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Uses 2-ASK modulation (1 bit/symbol)Data rates for USB 2.0 (480 Mbit/s) BW = (480 Mbit/s)/(1 bit/symbol) = 480 MHz ~= 500 MHz

Note: ASK signal requires a bandwidth equal to its baud (symbol rate)

- FFI membrane design rules provide excellent line width control for microwave circuits.
- With FAB variations of +/- 2 um allows us to hold the center attenuation to +/- 0.4 dB
- Designed on 2 metal layer membrane
- Coupler attenuator technology available for new membrane design.

50 Ohm Trick

- Observed large improvement when the resistor is mounted in a non-standard configuration.
 - Normal: RL < -10 dB @ ~30 GHz
 - Non-standard: RL < -10 dB @ ~65 GHz
 - Best used with 60 GHz coupler





Simulation

Simulation:

- The coupler design was simulated in HFSS
- The red trace is a gap of 42 um and green trace is for 52 um. Insertion Loss (IL):
- The simulated IL at 60 GHz is reasonable.
- Model predicted 52 um achieves the required 26 dB of attenuation. **Return Loss (RL):**
- RL=-25 dB at 60 GHz is acceptable.



HFSS Simulation

Simulated Coupler Return Loss (RL)



Measurements

(Validation)

- All 8 sites have an IL of approximately 29 dB. This is 3 dB below the simulated IL of 26 dB.
- Future work to perform additional work to identify why there is a 3 dB delta
- 3 dB more of IL is a benefit. It moves the receiver into a more linear region of operation.

IL For Sites 1-8 + HFSS Simulation (green)



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Data is fc = 60 GHz for 8 sites on a core.



Φ

101

CPW

The final membrane (Attenuator Core):

- x8 design with no RF traces routed off the membrane
- 8 couplers (attenuator) designed into the south wing of the membrane
- final attenuator design results in 29 dB of attenuation



Validation

Validation Process With RSSI (20k Die)
Product Improvement



Validation Validation Process With RSSI (20k Die)

Comparing legacy and attenuator core:

- StdDev of legacy core is 5x that of attenuator core (36 mV to 6 ~ 9 mV)
- CpK of attenuator core is above 2 (now passing)
- Initially 20k die tested (small sample)
- These results are a MAJOR achievement

RSSI (P_{IN}) Measured for Complete Wafer Using x8 P800s





Validation

Production Improvement

- On production mode after ~200 k die tested, attenuation remains stable and site variation is ok
- No more event of yield loss

Legacy core **Attenuator core** 300 300 1 2 3 250 250 64 200 200 5 150 8 🔘 Reference noints: Reference - Median points 100 - Media 100 50 k5tv9354 4 8 Count 85 87 87 87 87 87 17472 Median 173.928 176.9 155.553 130.895 Count 16469 16879 17080 17334 17643 18249 18359 213.31 245 478 213.961 188.096 107.779 Outliers 0 5 0 2 Median 135.079 119.563 145.732 103.748 118.195 122.37 97.1085 StdDev 5.98824 5 08933 5.20672 5.01638 4.24311 5 6634 6.37692 5.31978 Outliers 215 420 196 251 156 135 268 277 CpkProd 6.17233 6.23687 7.79846 6.66759 6.87201 5.64345 4.74336 2.83585 StdDev 5.74464 6.23171 5.95228 6.72144 5.28731 7.03742 5.41687 4.86239 CpkProd 6.54427 7.83726 5.7852 6.69751 7.21896 5.6074 7.52841 6.66089 Site » Category

RSSI (PIN) Measured for Complete Wafer Using x8 P800s

115 mV of delta for median values

50 mV of delta for median values

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Conclusion

- By moving attenuators to the membrane, attenuation over 8 test sites showed an improved standard deviation of 0.35 dB on two membranes, where the previous membrane version showed 1.5 dB. This amounts to a 77% standard deviation reduction.
- Additionally with the attenuator core:
 - RSSI hump has been resolved.
 - In production STMicroelectronics observed very good predictability and stability of core performance
 - STMicroelectronics considers this a great achievement on their production test

Finish



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